

**Notice of References Cited**

Application/Control No.  
09/898,321

Applicant(s)/Patent Under  
Reexamination  
STREET ET AL.

Examiner  
Paul E Brock II

Art Unit  
2815

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,587,591	12-1996	Kingsley et al.	257/59
	B	US-2002/0135041	09-2002	Kunikiyo, Tatsuya	257/510
	C	US-5,712,494	01-1998	Akiyama et al.	257/59
	D	US-6,337,284	01-2002	Hwang et al.	438/710
	E	US-5,789,737	08-1998	Street, Robert A.	250/208.1
	F	US-5,623,161	04-1997	Fukuda et al.	257/649
	G	US-5,262,649	11-1993	Antonuk et al.	250/370.09
	H	US-3,846,820	11-1974	Lampe et al.	257/443
	I	US-6,064,118	05-2000	Sasaki, Makoto	257/758
	J	US-5,449,953	09-1995	Nathanson et al.	257/728
	K	US-5,216,537	06-1993	Hornbeck, Larry J.	438/23
	L	US-4,141,055	02-1979	Berry et al.	361/778
	M	US-6,078,088	06-2000	Buynoski, Matthew S.	257/410

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Mulato et al., "Simulated and measured data-line parasitic capacitance of amorphous silicon large-area image sensor arrays", J. Applied Physics, vol. 89, page 638 (2000)
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.